Notice of References Cited Application/Control No. 10/615,565 Reexamination WITTE ET AL. Examiner Cheukfan Lee Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,650,445	11-2003	Witte et al.	358/509
*	В	US-6,178,015	01-2001	Lee et al.	358/486
*	С	US-5,822,052	10-1998	Tsai, Jenn-Tsair	356/229
*	D	US-6,954,292	10-2005	Inoue, Toshiyuki	358/475
*	E	US-6,330,083	12-2001	Nabeshima et al.	358/474
	H.	US-		<u>-</u>	
	G	US-			
	H	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	J	•					
	>						
	W						
	x						

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